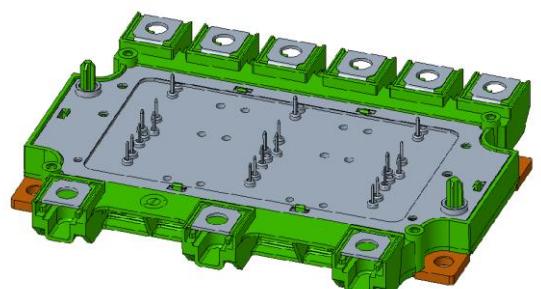


**HP1-DC6i Trench-Field Stop IGBT MODULE****CCGN600T75SD HP1DC6i Trench-Field Stop IGBT module**

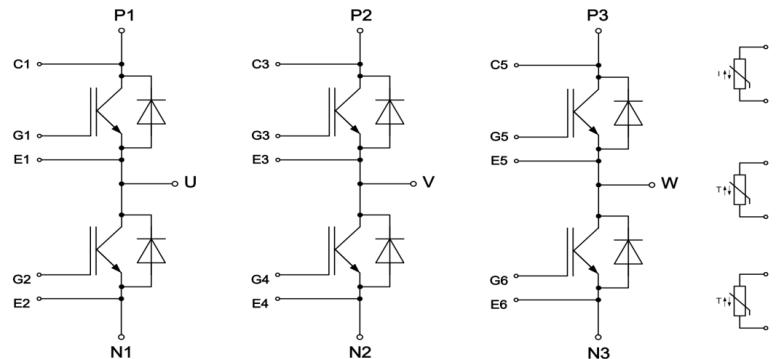
V_{CES}	V_{CESat}		I_{CN} / I_{CRM}
750V	$T_{vj}=25^{\circ}\text{C}$ @ 350A	1.31V	600A/1200A
	$T_{vj}=175^{\circ}\text{C}$ @ 350A	1.35V	

DESCRIPTION

CCGN600T75SD designed for a 150°C junction operation temperature, the module accommodates a 3-phase Six-Pack configuration of Trench-Field Stop IGBT and matching emitter controlled diodes.

**FEATURES**

- Low Switching Losses
- Low V_{CESat}
- 2.5kV AC 1min Insulation
- Blocking voltage 750V
- Low Q_g and C_{rss}
- Low Inductive Design
- High Power Density
- Direct Cooled Base Plate with Ribbon Bonds
- High Creepage and Clearance Distance
- Integrated NTC temperature sensor
- RoHS compliant
- AQG324 Qualified

EQUIVALENT CIRCUIT**APPLICATIONS**

- Automotive Applications
- Hybrid Electrical Vehicles (H)EV
- Commercial Agriculture Vehicles
- Motor Drives
- Optimized for automotive applications with DC link voltages up to 470V

CHARACTERISTICS VALUES

MAXIMUM RATED VALUES(IGBT)

Parameter	Symbol	Conditions	Values	Units
Collector-emitter voltage	V_{CES}	$T_{vj}=25^\circ C, V_{GE}=0V$	750	V
Implemented collector current	I_{CN}		600	A
Continuous DC collector current	$I_{C\text{ nom}}$	$T_F=80^\circ C, T_{vj\text{ max}}=175^\circ C$	350 ¹⁾	A
Repetitive peak collector current	I_{CRM}	$t_p=1ms, T_{vj}=25^\circ C$	1200	A
Gate-emitter peak voltage	V_{GES}	$T_{vj}=25^\circ C$	± 30	V
SC data	I_{SC}	$V_{GE}\leq 15V, V_{CC}=400V, t_p\leq 5\mu s, V_{CEmax}=V_{CES}-L_{SCE} \cdot di/dt, T_{vj}=150^\circ C$	3750	A
Total power dissipation	P_{tot}	$T_F=75^\circ C, T_{vj\text{ max}}=175^\circ C$	625 ¹⁾	W

1) Verified by characterization / design not by test.

CHARACTERISTICS VALUES(IGBT)

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Collector-emitter saturation voltage	$V_{CE\text{ sat}}$	$I_C=350A, V_{GE}=15V, T_{vj}=25^\circ C$		1.31	1.55	V
		$I_C=350A, V_{GE}=15V, T_{vj}=150^\circ C$		1.35	1.61	V
		$I_C=350A, V_{GE}=15V, T_{vj}=175^\circ C$		1.37	1.66	V
Gate-emitter thresholdvoltage	$V_{GE\text{th}}$	$V_{CE}=V_{GE}, I_C=6.4mA$	$T_{vj}=25^\circ C$	5.9	6.1	V
			$T_{vj}=175^\circ C$	3.9		
Gate charge	Q_G	$V_{GE}=-8V...+15V$		3.5		μC
Integrated gate resistor	R_G	$T_{vj}=25^\circ C$		1		Ω
Input capacitance	C_{ies}	$T_{vj}=25^\circ C, f=1MHz, V_{GE}=0V, V_{CE}=50V$		28		nF
Output capacitance	C_{oes}	$T_{vj}=25^\circ C, f=1MHz, V_{GE}=0V, V_{CE}=50V$		0.65		nF
Reverse transferencecapacitance	C_{res}	$T_{vj}=25^\circ C, f=1MHz, V_{GE}=0V, V_{CE}=50V$		0.18		nF
Collector-emitter cut-offcurrent	I_{CES}	$V_{CE}=750V, V_{GE}=0V$	$T_{vj}=25^\circ C$		0.85	mA
			$T_{vj}=175^\circ C$	4		
Gate-emitter leakagecurrent	I_{GES}	$V_{CE}=0V, V_{GE}=20V, T_{vj}=25^\circ C$			380	nA
Turn-on delay time,inductive load	t_{don}	$I_C=350A, V_{CE}=400V, V_{GE}=-8V/+15V, R_{Gon}=R_{Goff}=5\Omega$	$T_{vj}=25^\circ C$		315	ns
			$T_{vj}=150^\circ C$		330	
			$T_{vj}=175^\circ C$		340	
Rise time, inductive load	t_r	$I_C=350A, V_{CE}=400V, V_{GE}=-8V/+15V, R_{Gon}=R_{Goff}=5\Omega$	$T_{vj}=25^\circ C$		75	ns
			$T_{vj}=150^\circ C$		90	
			$T_{vj}=175^\circ C$		95	
Turn-off delay time,inductive load	t_{doff}	$I_C=350A, V_{CE}=400V, V_{GE}=-8V/+15V, R_{Gon}=R_{Goff}=5\Omega$	$T_{vj}=25^\circ C$		785	ns
			$T_{vj}=150^\circ C$		885	
			$T_{vj}=175^\circ C$		935	
Fall time, inductive load	t_f	$I_C=350A, V_{CE}=400V, V_{GE}=-8V/+15V, R_{Gon}=R_{Goff}=5\Omega, L_s=25nH$	$T_{vj}=25^\circ C$		75	ns
			$T_{vj}=150^\circ C$		75	
			$T_{vj}=175^\circ C$		80	
Turn-on energy loss perpulse	E_{on}	$I_C=350A, V_{CE}=400V, V_{GE}=-8V/+15V, R_{Gon}=R_{Goff}=5\Omega, L_s=25nH$	$T_{vj}=25^\circ C$		8.2	mJ
			$T_{vj}=150^\circ C$		16	
			$T_{vj}=175^\circ C$		17.5	
			$T_{vj}=25^\circ C$		16.5	
	E_{off}					mJ

Turn-off energy loss perpulse		di/dt=6800A/μs(T_vj 25°C) di/dt=3500A/μs(T_vj 150°C), dv/dt=3850V/μs(T_vj 25°C), dv/dt=3300V/μs(T_vj 150°C)	T_vj =150°C T_vj =175°C	25.4 26.6		mJ mJ
Thermal resistance, junctionto cooling fluid	R_{thJF}	Per IGBT, $\Delta V/\Delta t$ =10dm³/min, T_F =75°C			0.16	K/W

MAXIMUM RATED VALUES(Diode)

Parameter	Symbol	Conditions	Values	Units
Repetitive peak reverse voltage	V_{RRM}	T_vj =25°C	750	V
Implemented forward current	I_{FN}		600	A
Continuous forward current	I_F		350 ¹⁾	A
Maximum repetitive forward current	I_{FRM}	t_p =1ms	1200	A
I^2t -value	I^2t	V_R =0V, t_p =10ms, T_vj =150°C	14500	A ² s
		V_R =0V, t_p =10ms, T_vj =175°C	12500	

1) Verified by characterization / design not by test.

CHARACTERISTICS VALUES(Diode)

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Forward voltage	V_F	I_F =350A, V_{GE} =0V,	T_vj =25°C	1.47		V
			T_vj =150°C	1.37		V
			T_vj =175°C	1.33		V
Peak reverse recovery current	I_{RM}	I_F =350A, V_R =400V, V_{GE} =-8V di _F /dt=3950A/μs (T_vj 150°C)	T_vj =25°C	207		A
			T_vj =150°C	317		A
			T_vj =175°C	337		A
Recovered charge	Q_r	T_vj =25°C di _F /dt=3950A/μs (T_vj 150°C)	T_vj =25°C	24.3		μC
			T_vj =150°C	47.9		μC
			T_vj =175°C	55.8		μC
Reverse recovery energy	E_{rec}	T_vj =25°C T_vj =150°C T_vj =175°C	T_vj =25°C	2.1		mJ
			T_vj =150°C	5.5		mJ
			T_vj =175°C	7.2		mJ
Thermal resistance, junction to cooling fluid	R_{thJF}	Per diode, $\Delta V/\Delta t$ =10dm³/min, T_F =75°C			0.25	K/W

NTC-THERMISTOR

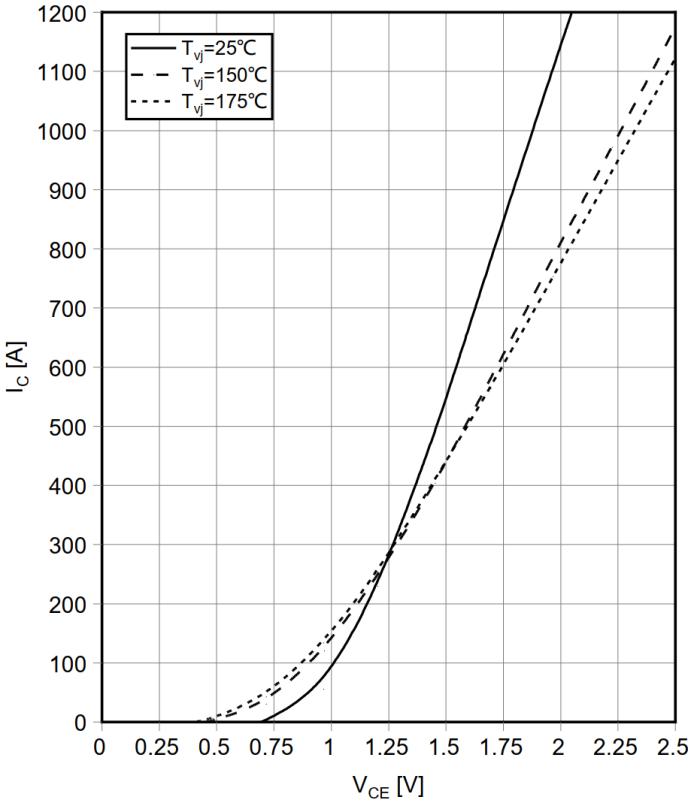
Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Rated resistance	R_{25}	T_C =25°C		5.0		KΩ
Deviation of R100	$\Delta R/R$	T_C =100°C, R_{100} =493Ω	-3		3	%
Power dissipation	P_{25}	T_C =25°C			60	mW
B-value	$B_{25/50}$	$R_2=R_{25} \exp[B_{25/50}(1/T_2-1/(298.15K))]$		3375		K
B-value	$B_{25/80}$	$R_2=R_{25} \exp[B_{25/80}(1/T_2-1/(298.15K))]$		3411		K
B-value	$B_{25/100}$	$R_2=R_{25} \exp[B_{25/100}(1/T_2-1/(298.15K))]$		3433		K

CHARACTERISTICS VALUES(MODULE)

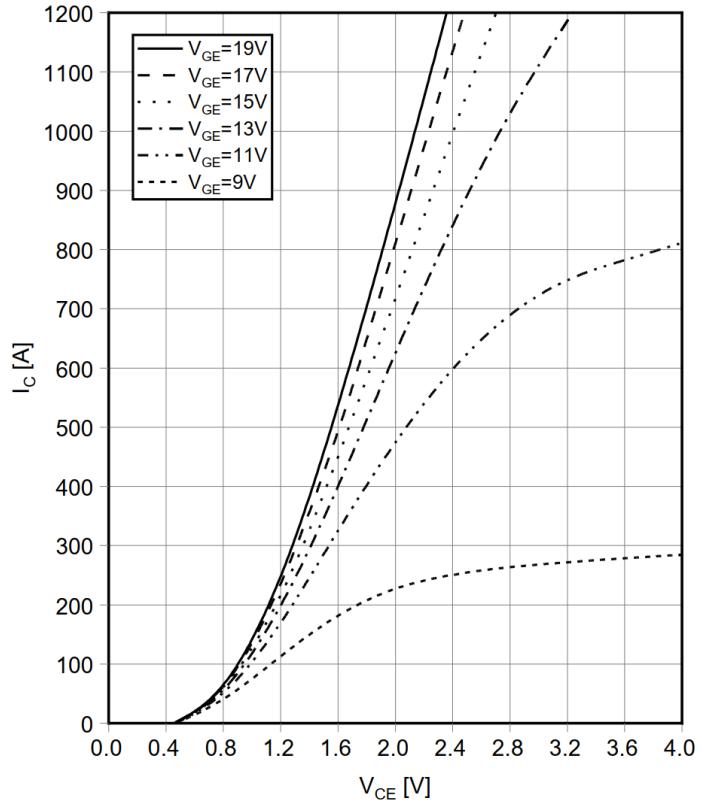
Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Maximum junction temperature	T _{vj max}				175	°C
Temperature under switchingconditions	T _{vj op}		-40		175	°C
Storage temperature	T _{stg}		-40		150	°C
Stray inductance module	L _{SCE}			15		nH
Module lead resistance, terminals-chip	R _{CC+EE}	T _{vj} =25 °C, per switch		0.9		mΩ
Isolation test voltage	V _{isol}	RMS, f=50Hz, t=1min		2.5		kV
Creepage distance	ds	Terminal to heatsink		18.2		mm
		Terminal to terminal		8.2		mm
Clearance distance in air	da	Terminal to heatsink		18.2		mm
		Terminal to terminal		5.9		mm
Comperative tracking index	CTI		>200			
Mounting torque for module mounting	M1	Screw M5 baseplate to heatsink	1.8	2.0	2.2	N.m
	M2	Screw M3 EJOT Delta PCB to frame	0.45	0.50	0.55	
Mounting torque for module mounting	M3	Screw M6	3		6	
Internal isolation	-	Basic insulation	Al ₂ O ₃			-
Material of module baseplate	-		Cu+Ni			-
Dimensions	L x W x H		140x112.6x30.5			mm
Weight	G		620			g

CHARACTERISTICS DIAGRAMS

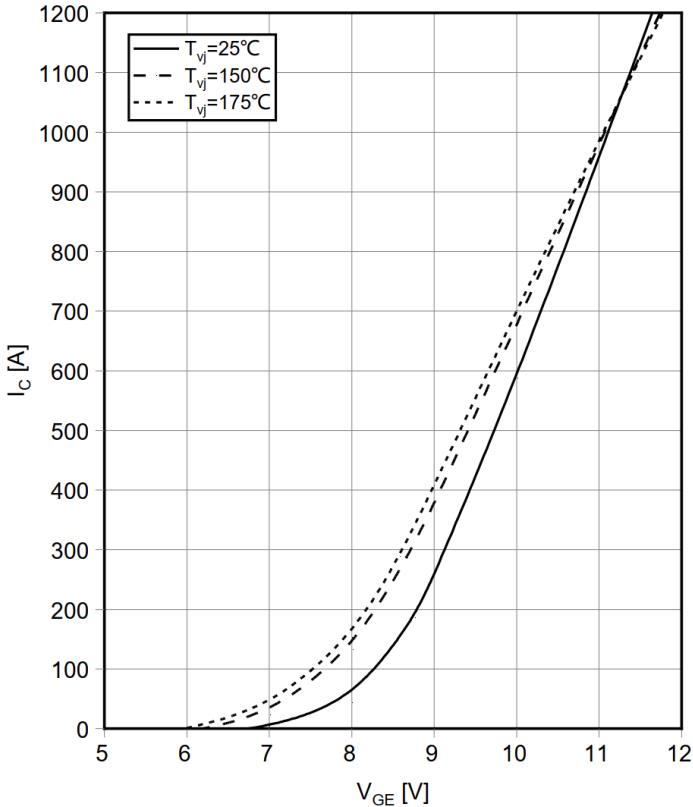
Output characteristic IGBT, Inverter(typical)
 $I_C=f(V_{CE})$, $V_{GE}=15V$



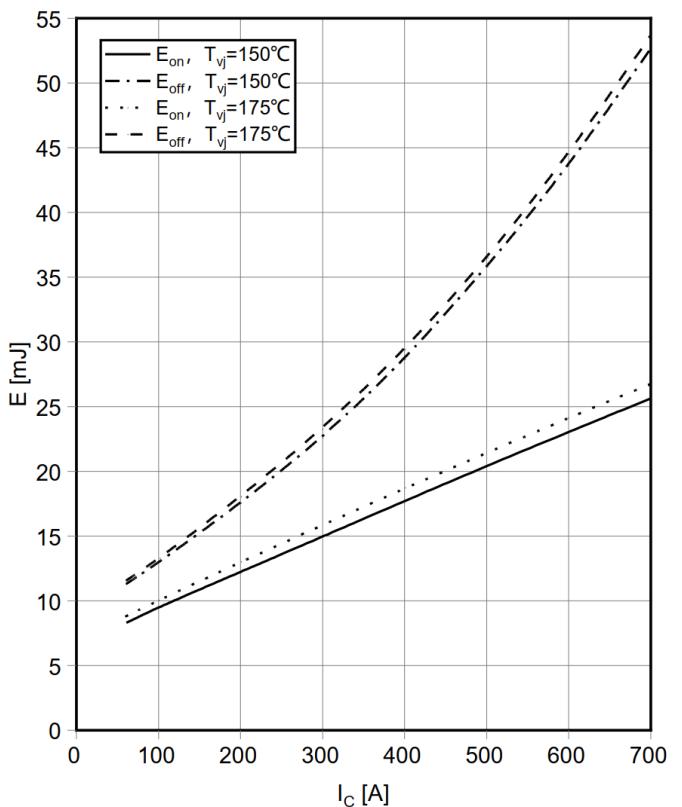
Output characteristic IGBT, Inverter(typical)
 $I_C=f(V_{CE})$, $T_{vj}=150^\circ C$



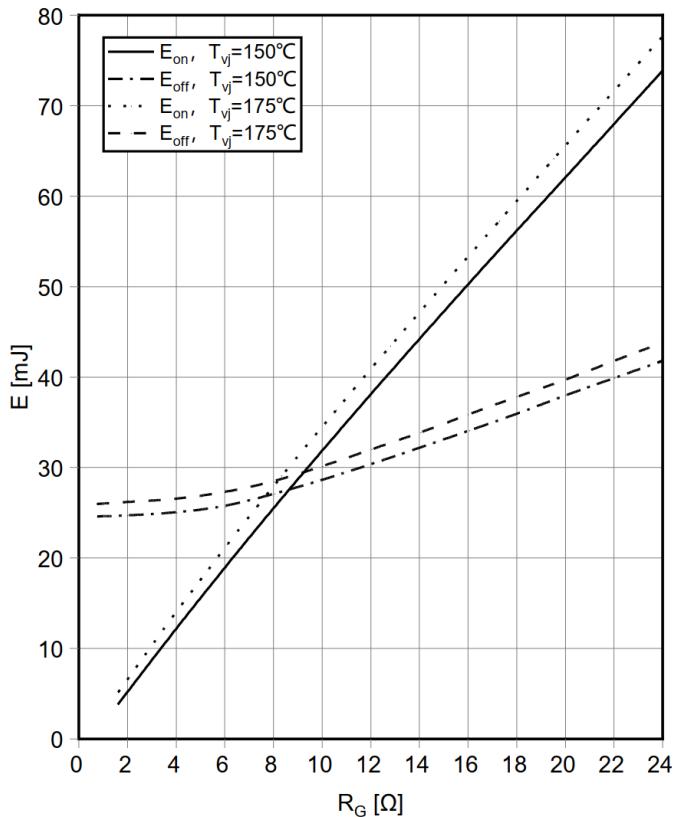
Transfer characteristic IGBT, Inverter(typical)
 $I_C=f(V_{GE})$, $V_{CE}=20V$



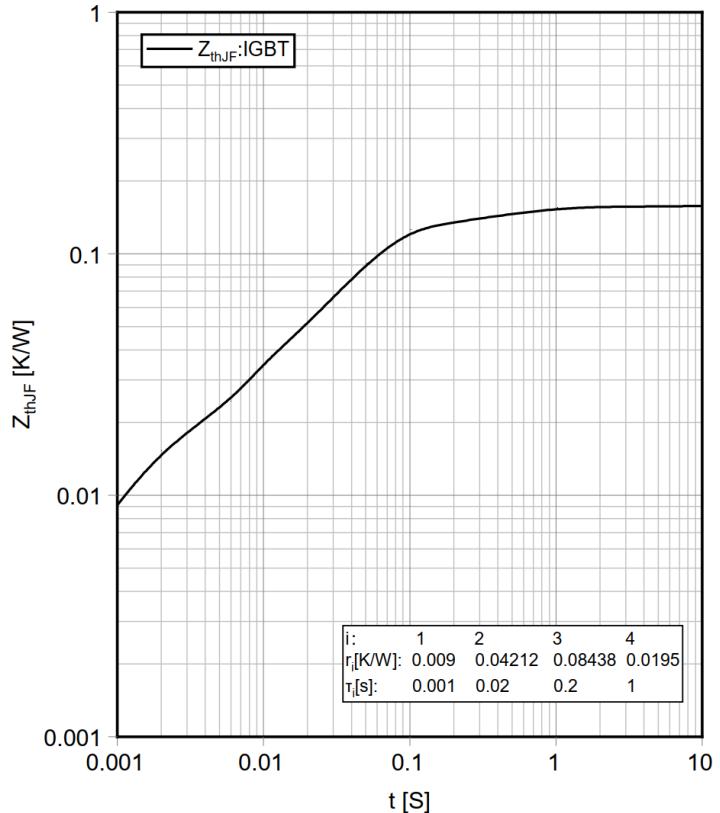
Switching losses IGBT, Inverter(typical)
 $E_{on}=f(I_C)$, $E_{off}=f(I_C)$, $V_{GE}=-8/+15V$, $R_{Gon}=R_{Goff}=5\Omega$, $V_{CE}=400V$



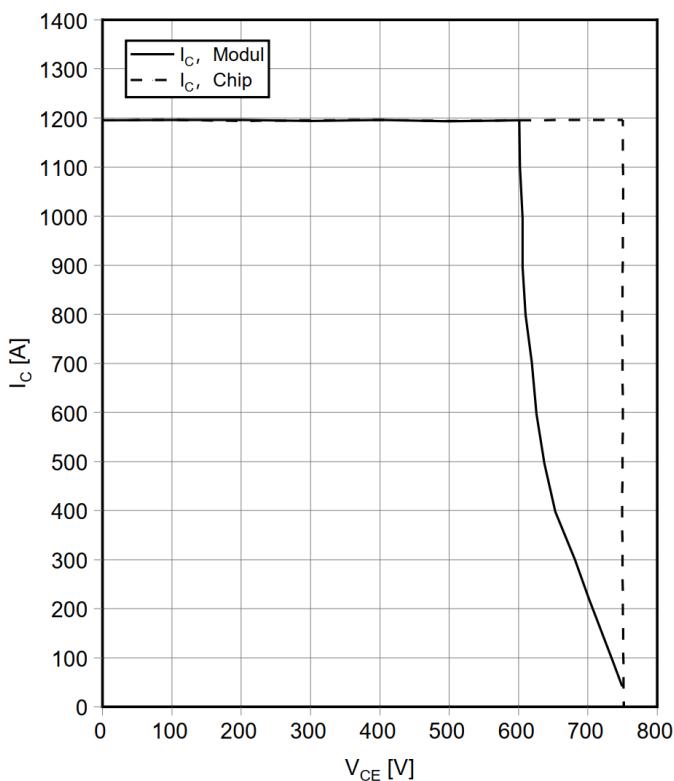
Switching losses IGBT, Inverter(typical)
 $E_{on}=f(R_G)$, $E_{off}=f(R_G)$, $V_{GE}=-8/+15V$, $I_C=350A$, $V_{CE}=400V$



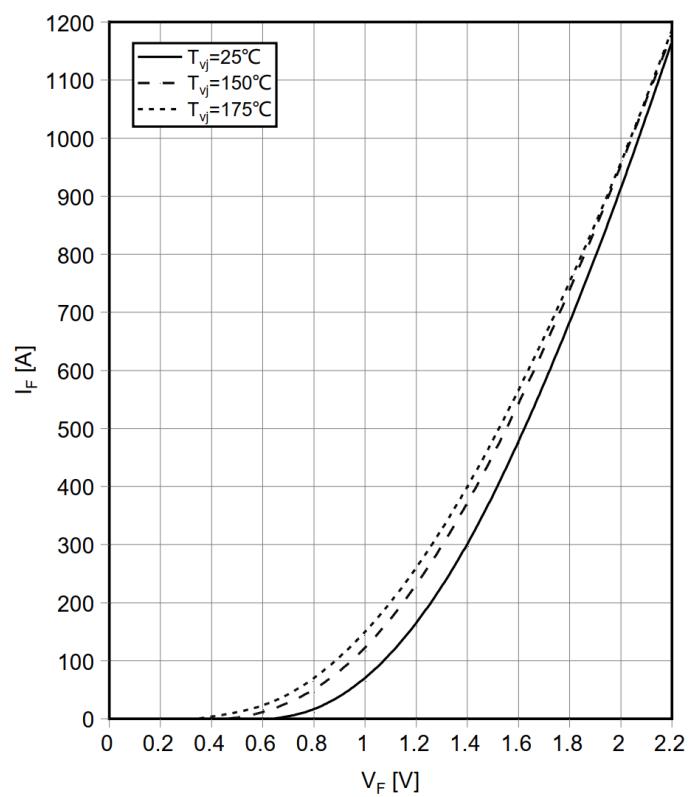
Transient thermal impedance IGBT, Inverter
 $Z_{thJF}=f(t)$



Reverse bias safe operating area IGBT, Inverter(RBSOA)
 $I_C=f(V_{CE})$, $V_{GE}=-8V/+15V$, $R_{Goff}=5\Omega$, $T_{vj}=175^\circ C$

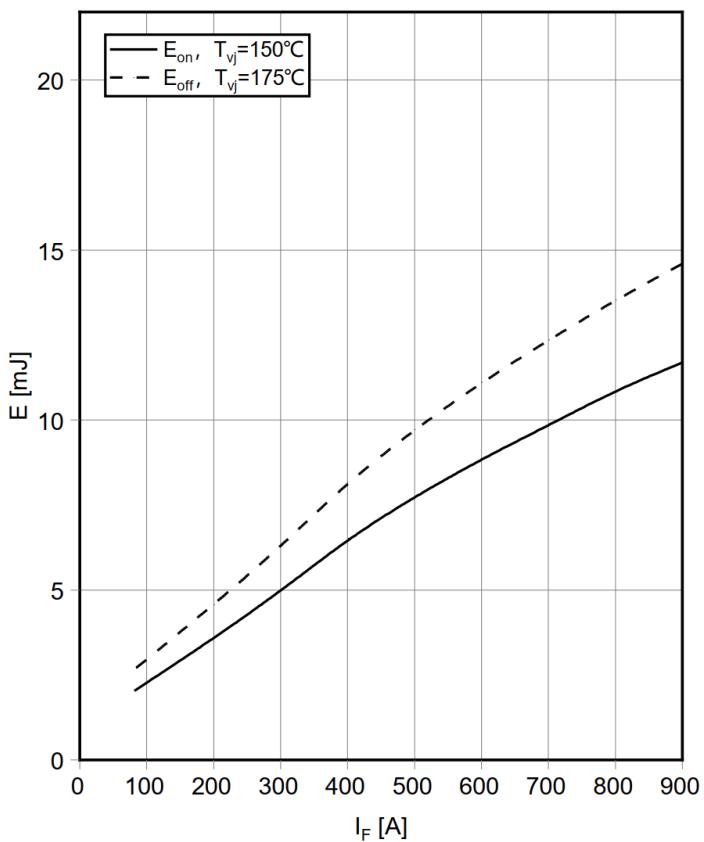


Forward characteristic of Diode, Inverter(typical)
 $I_F=f(V_F)$



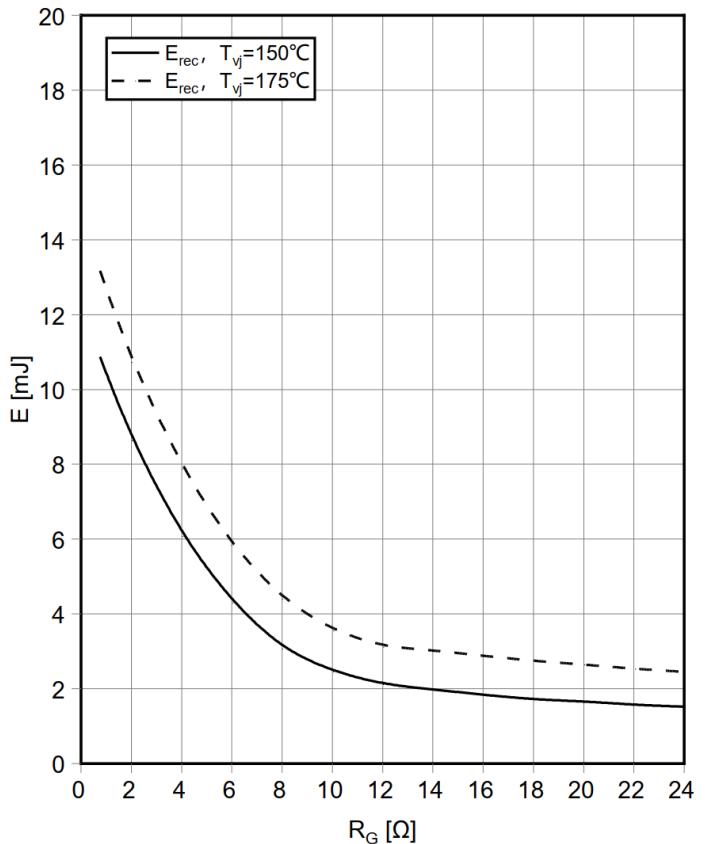
Switching losses Diode, Inverter(typical)

$E_{rec}=f(I_F)$, $R_{Gon}=5\Omega$, $V_{CE}=400V$

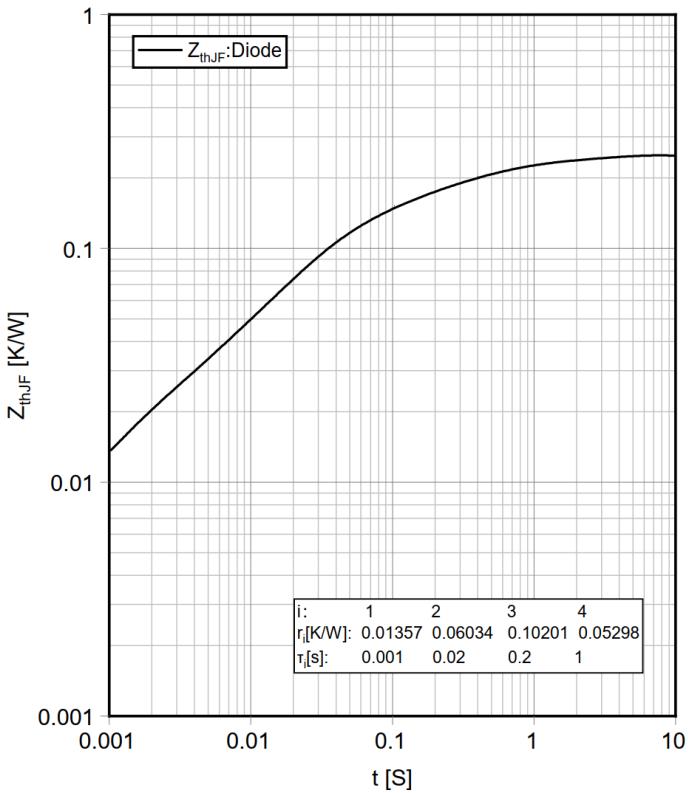


Switching losses Diode, Inverter(typical)

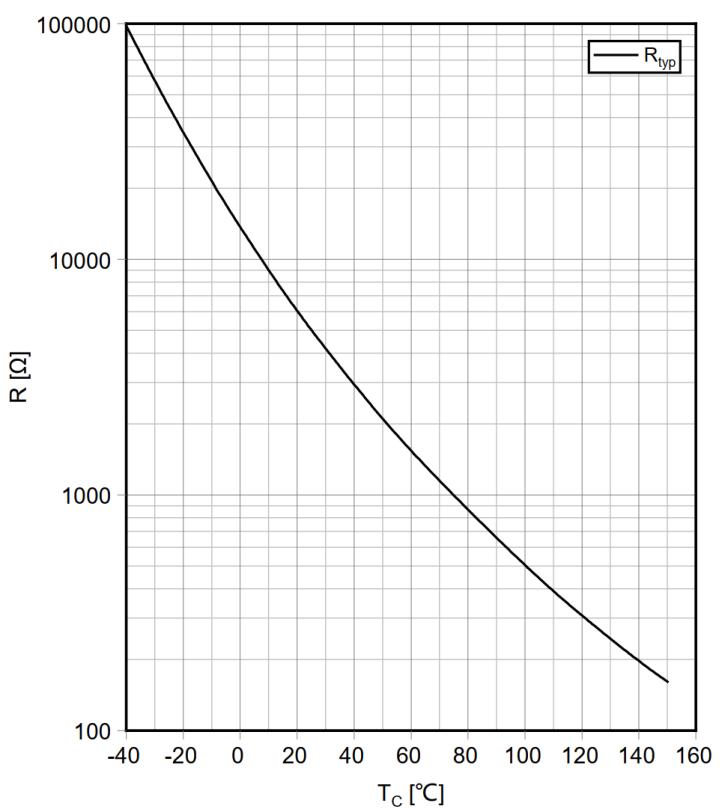
$E_{rec}=f(I_F)$, $I_F=350A$, $V_{CE}=400V$



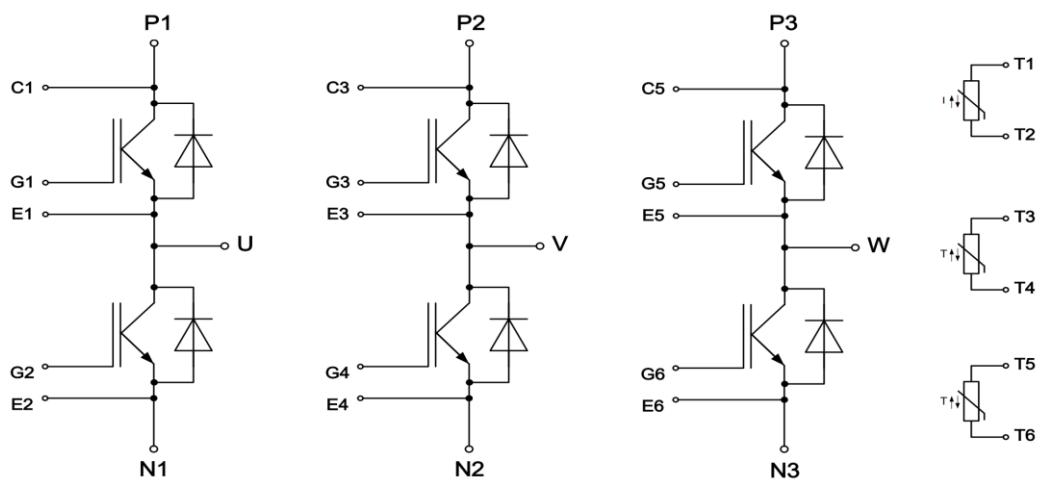
Transient thermal impedance Diode,Inverter
 $Z_{thJF}=f(t)$



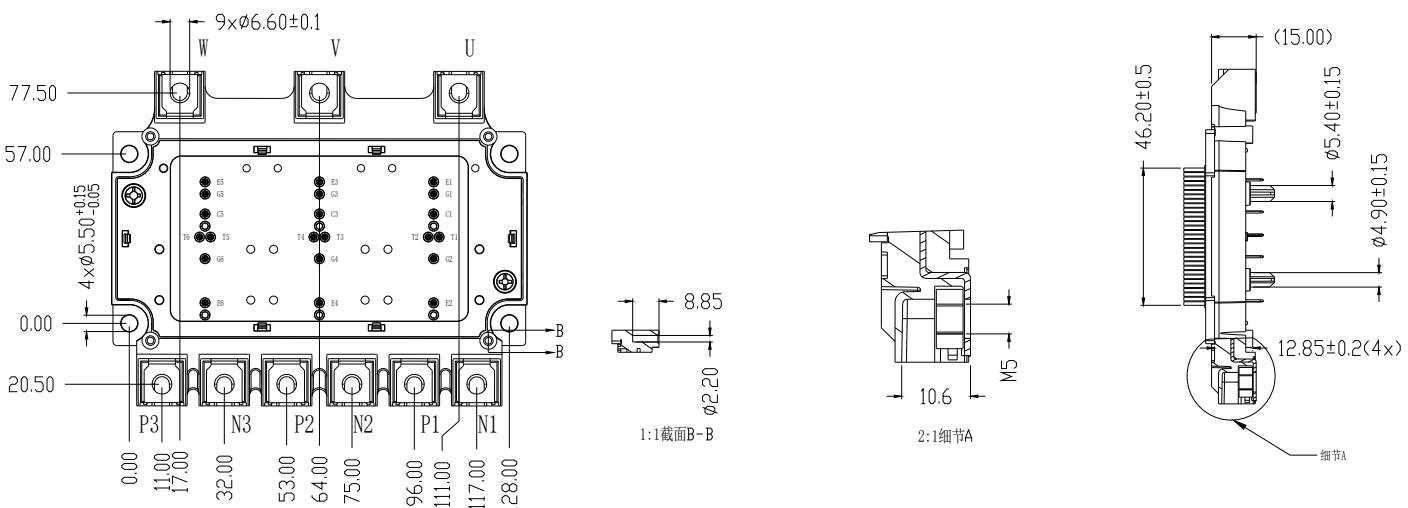
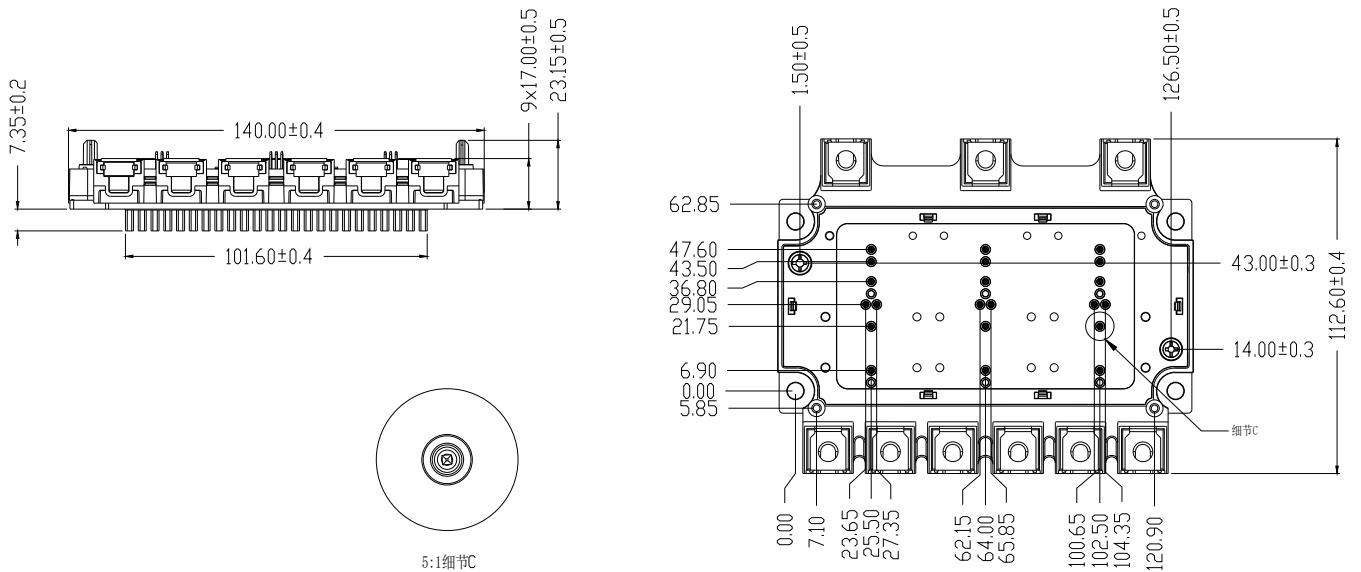
NTC-Thermistor-temperature characteristic(typical)
 $R=f(T)$



CIRCUIT DIAGRAM



PACKAGE OUTLINES



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Date of change	Rev #	revise content
2023/04/21	A/0	/